FOCUS HIS 14 HD HIGH DENSITY VUV SOURCE

Ultimate UPS, ARPES, PEEM and µ-ARPES

Brochure

FOCUS

Voltar

Set / Adjust

VUV spot imaged with PEEM (25° grazing incidence)

FWHM

290 µm

600

Position on Sample (µm)

800

1000

Menu / Select

1,1

1,0

0,9

0.8

0,7

0,6

0.5

0.4

0.3

0,2 0,1 0,0

Vormalized Intensity

HIS 14

spot-profile

200

MADE IN

GERMANY

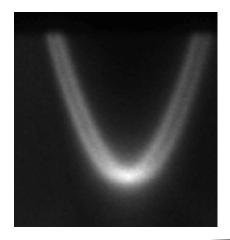
400

denina-

• 300 µm spot size

VUV SOURCE

- 50 x higher flux density (compared to non-focused source)
- Large working distance
- Ease of operation
- Discharge regulation
- Operating pressure down to 10⁻¹⁰ mbar range



Au (111) surface state with Rashba Splitting HeI excitation (21.2 eV) Dwell time 50 s measured with PHOIBOS 100 (SPECS GmbH)

Courtesy: Dr. L. Dudy, M. Scholz, Universität Würzburg

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Photo current Useful gas discharge lines: Spot diameter: Photon line width: Photon flux density: Source alignment: Pumping: Working distance: Insertion depth: Mounting flange: Operating pressure: Adjustment & Discharge control Cooling: Bake out temperature: Plasma Ignition: Capillary (mm):

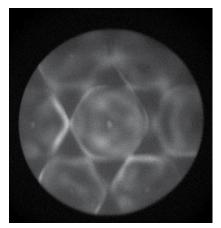
> 20 nA (biased Al foil, standard capillary)
He I/II, NeI/II, ArI/II, KrI/II, XeI/II, H (Lya, Lyβ)
< 300 μm (fwhm; 5:1 demagnifying optics)
< 2 meV (HeI radiation)
< 50 times compared to an unfocused source
CF 63 port aligner
2- or 3-stage differential pumping
Ca. 70 mm (clearance to measurement position)
Customized (to be defined)
DN 63 CF of DN 100 CF
Down to 10⁻¹⁰ mbar range

Via backside viewport

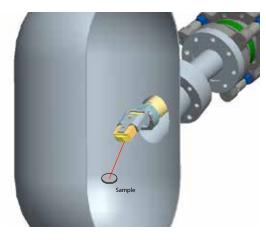
Water cooling Up to 250° C Automatic 0.8 / 1.2 / 1.7 (standard) / 2.2



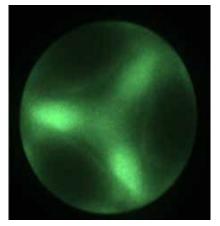
The VUV source power supply is a fully digital unit with integrated pressure measurement and automated plasma ignition. It delivers up to 1 kV anode voltage, up to 300 mA discharge current and a very stable discharge regulation.



Sample: Ag (111) , Fermi surface, He II excitation (40.8 eV) E - E_F = 40.8 eV Dwell time 1000 s Sample region ~ 50 μ m Measured with NanoESCA II Measured by: N.Weber, FOCUS GmbH



Application: HIS 14 HD retrofitted to an existing ARPES chamber.



Sample: Ag(111), d-bands HeI excitation (21.2 eV) $E-E_F = 15.5 eV$ Dwell time 5 s, sample region ~ 20 µm Measured with PEEM and Imaging Energy Filter (IEF) Measured by: N.Weber, FOCUS GmbH

